

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventors: Kenneth E. Knapp et al.

Serial No.: 09/500,380

Filed: February 8, 2000

Examiner: C. Renner

Docket No.: RR-1645

GAU: 2652

For: SUBMICRON TRACK-WIDTH POLE-TIPS FOR ELECTROMAGNETIC
TRANSDUCERS

April 12, 2004

MS No Fee Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Declaration of Kenneth E. Knapp
Under 37 C.F.R. § 1.131

I, Kenneth E. Knapp, declare:

1. I am an inventor of the invention claimed in U.S. Patent Application Serial Number 09/500,380, including independent claim 1, as amended on October 16, 2003.

2. Attached is a copy of an eight-page set of drawings entitled: "METHOD OF DEFINING SUB-0.5um NARROW TRACK," dated 5-24-99. These drawings show that I conceived the invention defined by independent claim 1 of the above-referenced patent application at least as early as May 24, 1999.

3. Patent protection was diligently pursued from on or before August 4, 1999 to the filing of U.S. Patent Application Serial Number 09/500,380 on February 8, 2000.

5. The above described conception and invention occurred in the United States, in and around Fremont, California.

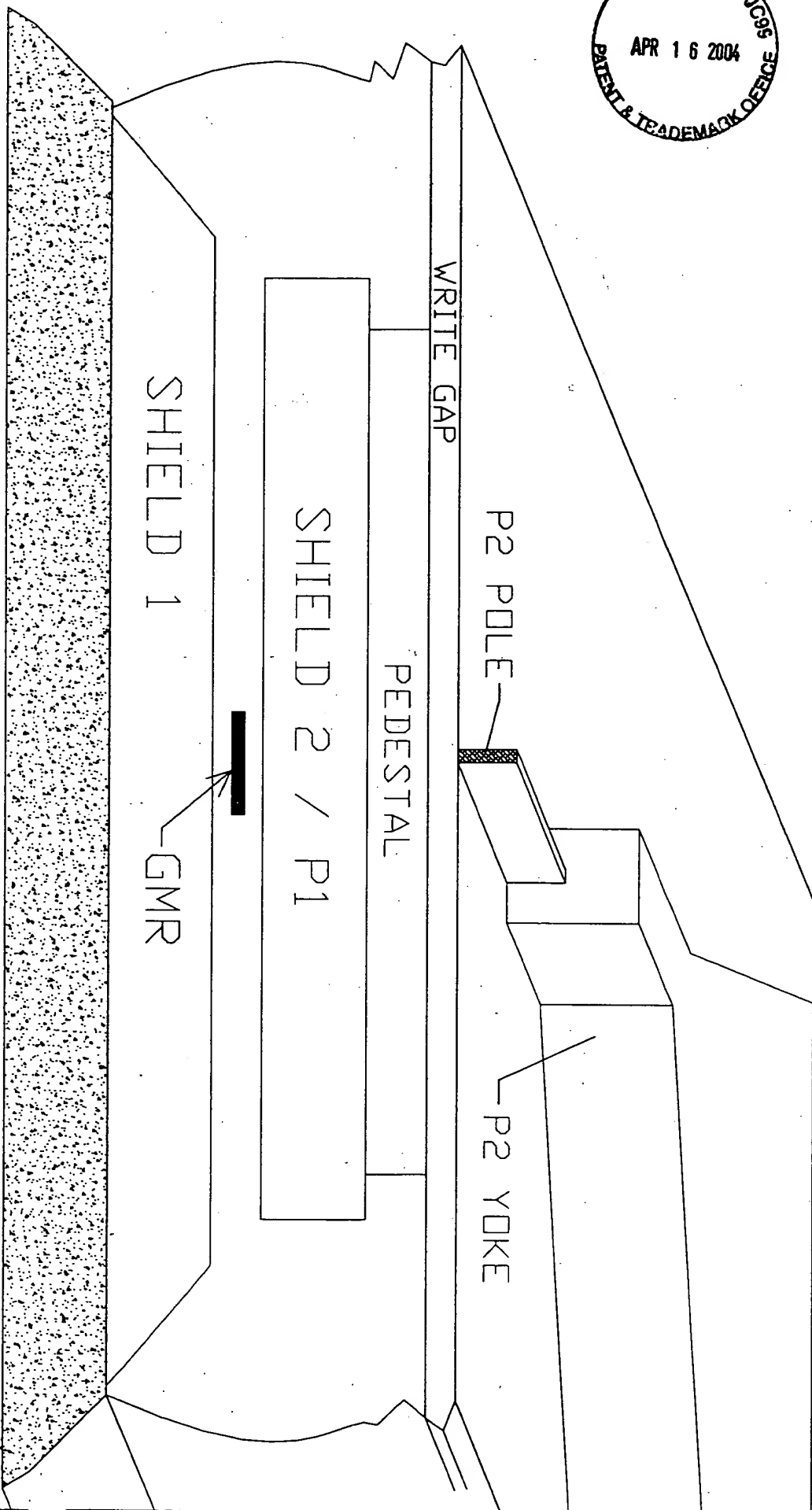
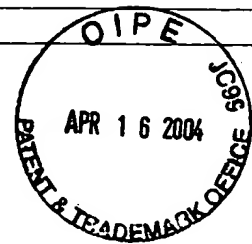
6. I hereby declare that all statements made herein of my own knowledge are true and that all statements made on information and belief are believed to be true, and further that these statements were made with the knowledge that willful false statements and the like so made are punishable by fine or imprisonment, or both under Section 1001,

#25
11/28/04

Title 18, of the United States Code, and that such willful false statements may jeopardize the validity of the application or any patent issued thereon.

Date: April 12, 2004

Kenneth E. Knapp
Kenneth E. Knapp



"METHOD OF DEFINING SUB-0.5um NARROW TRACK"

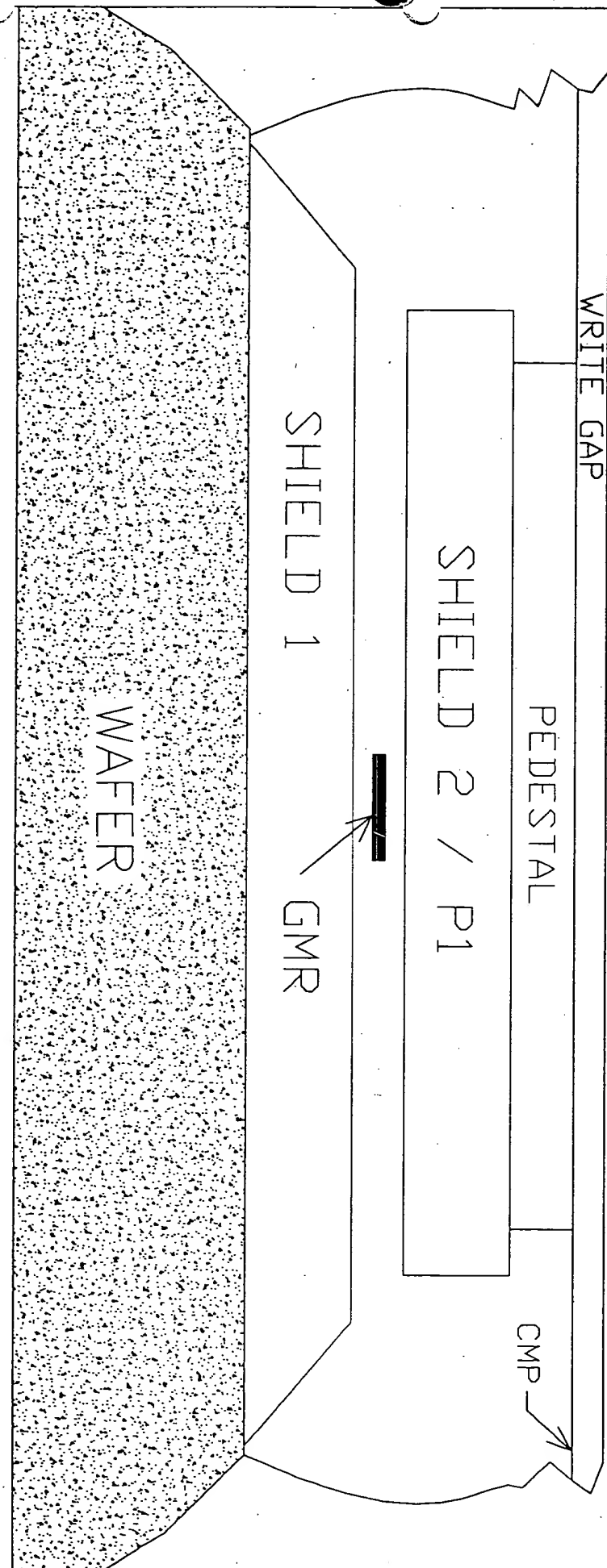
II

ABS VIEW OF NEW INVENTION

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	APPROVED ZHUPAI SHI	
	APPROVED RON BARR	

TITLE:		READ-RITE Corporation	
"METHOD OF DEFINING SUB-0.5um NARROW TRACK"		MASK DESIGN DEPT.	
FAX 510-683-7065			
SIZE	STITCH	DMO FILE	REV
B			
SCALE	SHEET 1 OF 9		

Sheet III



PROCESS STEPS:

- STEP 1) STANDARD 12 GBIT PROCESS TO PEDestal CMP
- STEP 2) DEPOSIT WRITE GAP, PROCESS COIL AND I2 (NOT SHOWN)



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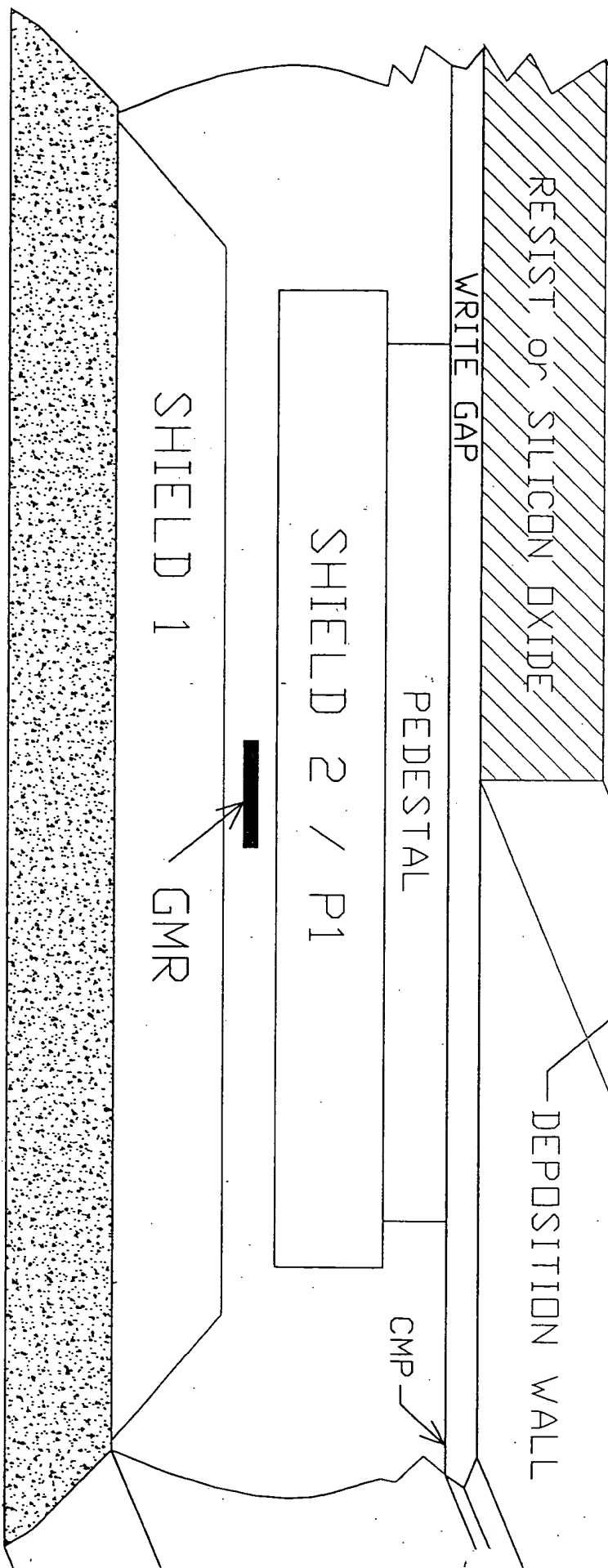
MASK DESIGN DEPT.
FAX 510-683-7065

TITLE: "METHOD OF DEFINING SUB-0.5um NARROW TRACK"

SIZE SYSTEM DWG FILE REV

SCALE SHEET 2 OF 9

Sheet IV

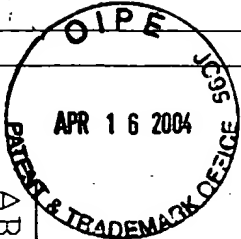


PROCESS STEPS:

STEP 3) CREATE PHOTORESIST OR SILICON DIOXIDE WALL

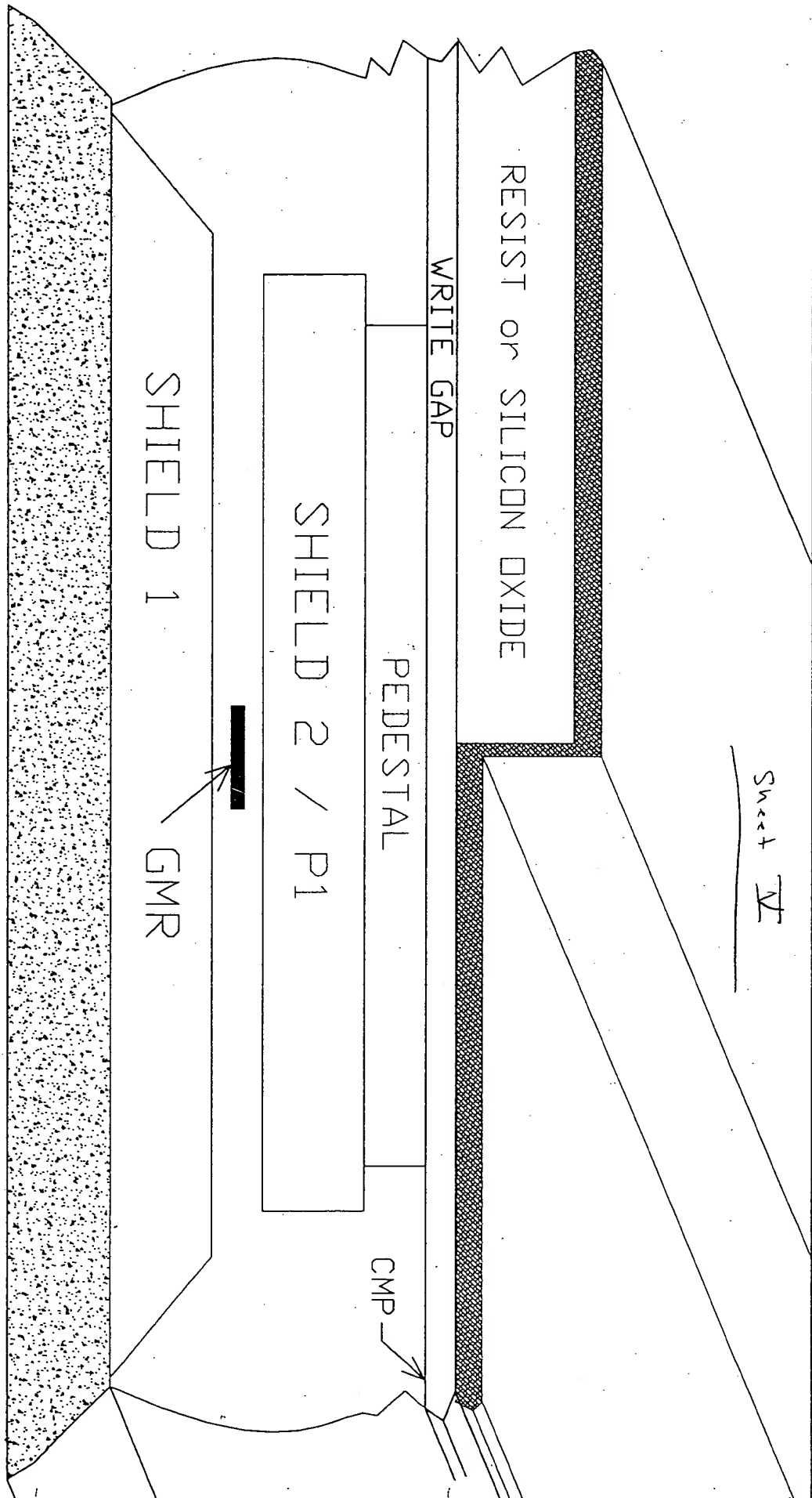
James C. Tran
11/11/77

ABS VIEW OF NEW INVENTION



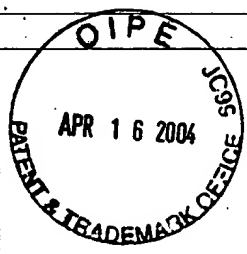
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SIZE B	SYSTEM	DWG FILE	REV	
SCALE	SHEET 3 OF 9			

Sheet IV



PROCESS STEPS:

STEP 4) DEPOSIT P2 MATERIAL



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TITLE: "METHOD OF DEFINING SUB-0.5um NARROW TRACK"			
SIZE	STYLED	DMO FILE	REV
B			
SCALE		SHEET 4 OF 9	

Sheet VI

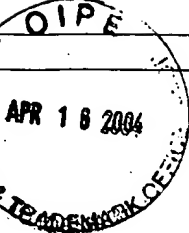
RESIST OR SILICON OXIDE

WRITE GAP

PEDESTAL

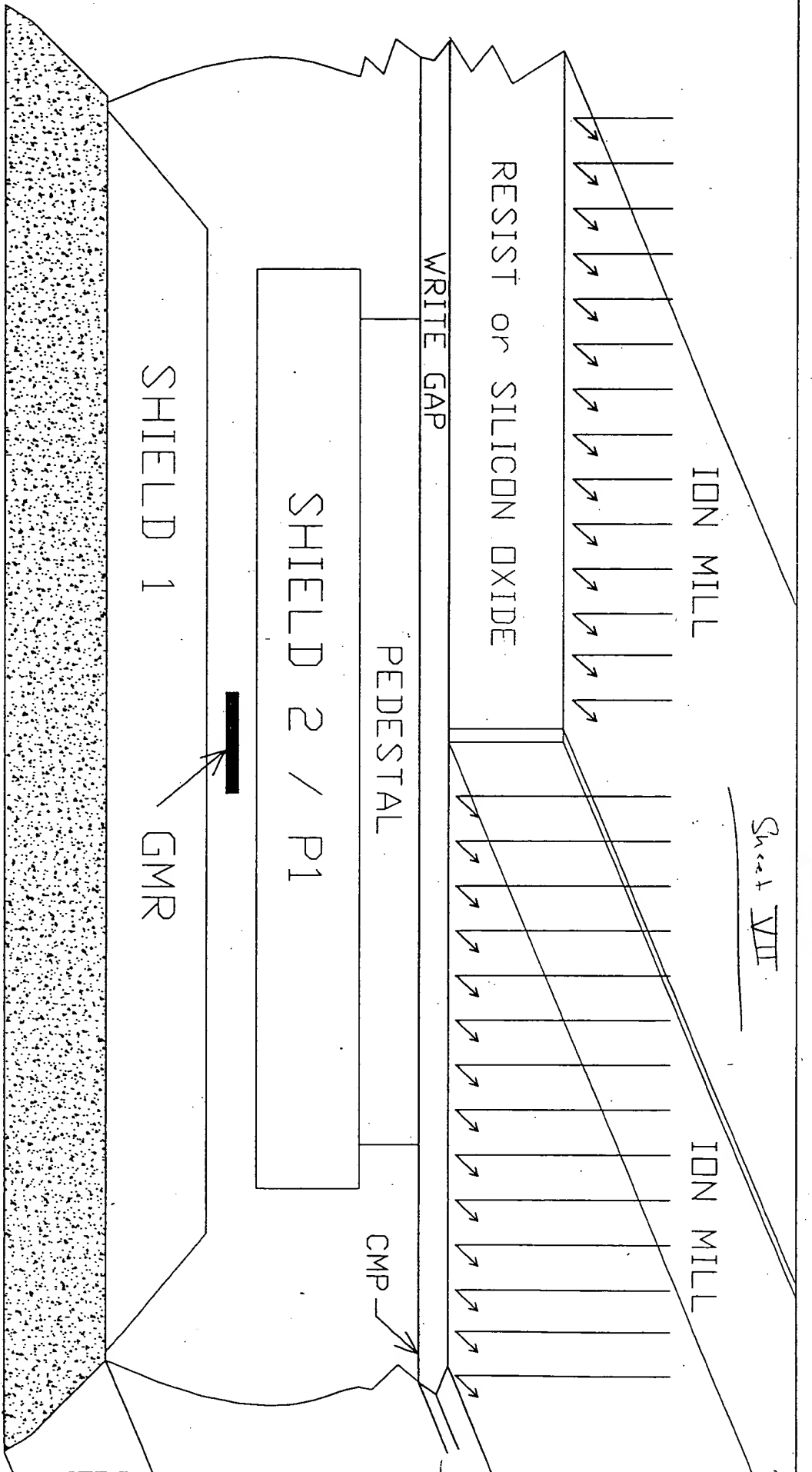
VERTICAL LAMINATIONS ARE POSSIBLE

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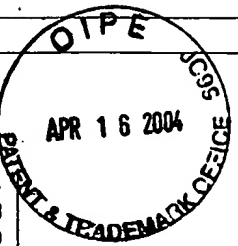
TITLE:		METHOD OF DEFINING SUB-0.5um NARROW TRACK	
READ-RITE Corporation		MASK DESIGN DEPT.	
FAX 510-683-7085			
SIZE	STYLED	DWG FILE	REV
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SCALE	SHEET 5 OF 9		



PROCESS STEPS:

STEP 5) ION MILL TO CREATE THE P2 STRUCTURE

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TITLE: "METHOD OF DEFINING SUB-0.5um NARROW TRACK"			
SCALE	SHEET 6 OF 9	REV	

Sheet VIII

TRACK WIDTH

WRITE GAP

PEDESTAL

SHIELD 2 / P1

CMP

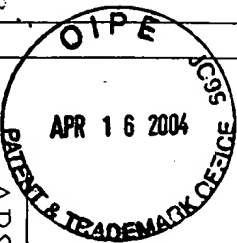
SHIELD 1

GMR

PROCESS STEPS:

STEP 6) REMOVE RESIST OR SILICON OXIDE WALL

ABS VIEW OF NEW INVENTION



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SIZE	STATUS	DATE FILE	REV
B			
SCALE		SHEET 7 OF 9	

Sheet IX

WRITE GAP

PEDESTAL

SHIELD 2 / P1

SHIELD 1

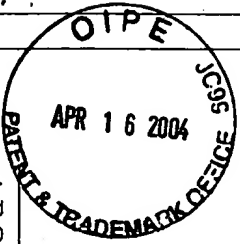
GMR

P2 YOKE

PROCESS STEPS:

STEP 8) MASK AND PLATE P2 YOKE

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FAX 510-683-7085

TITLE:

"METHOD OF DEFINING SUB-0.5um NARROW TRACK"

SIZE: 11x14

DWG FILE

REV

SCALE

SHEET 8 OF 9